PATENT APPLICATION

ATTORNEY DOCKET NO. 200207083-1

Confirmation No.:

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s):	Blaine Stackhouse et al.	Confirmation No.:				
Application No	:	Examiner:				
Filing Date:	Jun. 20, 2003	Group Art Unit:				
Title:	BIAS GENERATION HAVING ADJUSTABLE RANGE AN METAL PROGRAMMING	D RESOLUTION THROUGH				
Commissioner PO Box 1450						
Alexandria, VA	22313-1450					
	INFORMATION DISCLOSURE STATEMENT					

Sir:

Inventor(s):

This Information Disclosure Statement is submitted:

(X)	under 37 CFR 1.97(b), or (Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
()	under 37 CFR 1.97(c) together with either a: () Statement under 37 CFR 1.97(e), or () a \$180.00 fee under 37 CFR 1.17(p), or (After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
()	under 37 CFR 1.97 (d) together with a: () Statement under 37 CFR 1.97(e)(1) or (2), and () a \$180.00 fee set forth in 37 CFR 1.17(p). (Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$0.00 __ . At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account 08-2025 pursuant to 37 CFR 1.25.

- Applicant(s) submit herewith Form PTO 1449 Information Disclosure Citation together with copies, of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.
- () A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

"Express Mail" label no. EO 901 006 928 US

Date of Deposit Jun. 20, 2003

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Alexandria, VA Commissioner 22313-1450

Typed Name: J. Michael Johnson

Respectfully submitted,

Blaine Stackhouse et al.

J. Michael Johnson

Attorney/Agent for Applicant(s)

Reg. No. 37,856

Date: Jun. 20, 2003

Telephone No.: (775) 849-3085

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Sheet 1 of 1

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				ATTY, DOCKET NO.	Α	PPLICATION NO.	CONFIRMA	ATION N		
				200207083-1						
				APPLICANT Blaine Stackhouse et al.						
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XAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE		NAME Mehalel Melanson et al.		Pages, Columns, Lines Where Relevant Passages or Figures Appear			
	1A	6,256,241 B1	Jul. 3, 2001	Ме						
	1B	6,501,692 B1	Dec. 31, 2002	Ме						
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	1Q	Sanjay Sengu Test," Intel Te	pta et al., "Defect-E echnology Journal, (Based T Q1, 19	Fest: A Key Enabler 1 199, pp. 1-14.	for Succe	essful Migration	n to Structui	ral	
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